

Biometric Consortium 2003 Conference

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Dr. Donald P. D'Amato has been an employee of Mitretek Systems, Inc., and the MITRE Corporation for 16 years. He conducts engineering and performance analyses of systems involving digital image processing, biometrics technologies, and document image analysis. His recent work has addressed the design and analysis of automated face and fingerprint recognition systems for passport and visa processing. He has developed test patterns and analysis software that enable objective determination of image quality for images of various types of documents, as well as for fingerprint and face images. Dr. D'Amato has also maintained an interest in the processing of color images and has provided in-depth guidance to federal agencies and non-profit organizations concerning accurate, device-independent rendition of color.

Among the agencies he has supported are the US Department of State, Federal Bureau of Investigation, Department of Justice, National Institute of Standards and Technology, National Institutes of Health Information Technology Acquisition and Assessment Center, US Postal Service, Smithsonian Institution's National Museum of Natural History, Internal Revenue Service, and the Patent and Trademark Office.

Dr. D'Amato is a Senior Member of the IEEE. He received a Bachelor of Arts degree in Physics from Ohio Wesleyan University and Master of Science and Doctor of Philosophy degrees in Physics from Ohio State University.